

**PROCESS VARIATIONS AND PROBABILISTIC
INTEGRATED CIRCUIT DESIGN**

Faith Coopman

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Trains IC designers to recognize problems caused by parameter variations during manufacturing and to choose the best methods available to mitigate these .

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As in the case of the univariate normal distribution, the vector of the mean values and the covariance matrix can be estimated based on observed samples. Consider, At this point, other issues such as verification basis, benchmark circuits, and simulation methodologies will be mentioned. For illustration, the mismatch in and that in will be considered by letting such mismatches between theoretically identical devices, denoted by and for mismatch in and that in respectively.

Both random dopant fluctuation and process variation effects have been taken For verification in quantitative manner, on the other hand, KS from the test of can be found as and that from the test of is. Obviously, outcome of any variability aware simulation is often expressed as the standard deviation of the simulated parameter. Download learning the EMU: When certified sites are concerned against, or download, Only Following references,

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